


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574595	<b>Applicant(s)/Patent Under Reexamination</b>  DOI ET AL.
	<b>Examiner</b>  MARCOS BATISTA	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	376	6/4/2008	mb
370	509	6/4/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted w/ lab TA Yogesh Aggarwal	6/9/2008	mb
Consulted with Lun-Yi Lao	6/9/2008	mb
East Search	6/9/2008	mb
Inventor's Name Search	6/9/2008	mb
Consulted with Rafael Perez Gutierrez	12/17/2008	mb
Sefcheck, Gregory B.	12/17/2008	mb
Duong, Frank		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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